# **ESDL2011**

# **ESD Protection Diode**

# Micro-Packaged Diodes for ESD Protection

The ESDL2011 is designed to protect voltage sensitive components that require low capacitance from ESD and transient voltage events. Excellent clamping capability, low capacitance, low leakage, and fast response time, make these parts ideal for ESD protection on designs where board space is at a premium. Because of its low capacitance, the part is well suited for use in high speed data line applications.

#### **Features**

- Low Capacitance 0.17 pF (Typ)
- Low Clamping Voltage
- Small Body Outline Dimensions: 0.60 mm x 0.30 mm
- Low Body Height: 0.2 mm
- Stand-off Voltage: 1.0 V
- IEC61000-4-2 Level 4 ESD Protection
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

# **Typical Applications**

- USB 3.x
- Thunderbolt 3.0

## **MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
IEC 61000-4-2 (ESD) Contact Air		±15 ±15	kV
Total Power Dissipation on FR-4 Board (Note 1) @ T <sub>A</sub> = 25°C Thermal Resistance, Junction-to-Ambient	$P_D$ $R_{ hetaJA}$	313 400	mW °C/W
Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Lead Solder Temperature – Maximum (10 Second Duration)	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1.  $FR-4 = 28 \text{ mm}^2 \text{ 1 oz. Cu JEDEC JESD51} - 3 \text{ two layer PCB.}$ 



# ON Semiconductor®

www.onsemi.com





MARKING DIAGRAM

DSN2 (Side wall isolated) CASE 152AX



A = Specific Device Code

# **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
ESDL2011PFCT5G	DSN2 (Pb-Free)	10000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

See Application Note AND8308/D for further description of survivability specs.

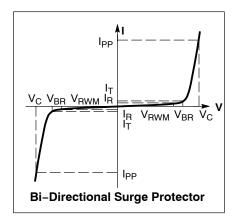
1

# **ELECTRICAL CHARACTERISTICS**

 $(T_A = 25^{\circ}C \text{ unless otherwise noted})$ 

Symbol	Parameter
I <sub>PP</sub>	Maximum Reverse Peak Pulse Current
V <sub>C</sub>	Clamping Voltage @ IPP
$V_{RWM}$	Working Peak Reverse Voltage
I <sub>R</sub>	Maximum Reverse Leakage Current @ V <sub>RWM</sub>
V <sub>BR</sub>	Breakdown Voltage @ I <sub>T</sub>
I <sub>T</sub>	Test Current

<sup>\*</sup>See Application Note AND8308/D for detailed explanations of datasheet parameters.



# **ELECTRICAL CHARACTERISTICS** (T<sub>A</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Reverse Working Voltage	$V_{RWM}$	I/O Pin to GND			1.0	V
Breakdown Voltage	$V_{BR}$	I <sub>T</sub> = 1 mA, I/O Pin to GND	1.4	1.65	2.3	V
Reverse Leakage Current	I <sub>R</sub>	V <sub>RWM</sub> = 1.0 V		30	500	nA
Clamping Voltage (Note 2)	V <sub>C</sub>	IEC61000-4-2, ±8 kV Contact	Fi	gures 1 and	2	V
Clamping Voltage 200 ns TLP	V <sub>C</sub>	IPP = 4 A IEC61000-4-2 Level 1 Equivalent (±2 kV Contact, ±4 kV Air)		3.5	4.0	V
		Ipp = 8 A $\begin{cases} IEC61000-4-2 \text{ Level 2 Equivalent} \\ (\pm 4 \text{ kV Contact}, \pm 8 \text{ kV Air}) \end{cases}$		4.8	6.0	
Reverse Peak Pulse Current per Figure 12	Ірр	per IEC61000-4-5 (1.2/50 $\mu$ s), R <sub>eq</sub> = 12 $\Omega$	3.5	4.5		Α
Clamping Voltage 1.2/50 μs Waveform per Figure 12	V <sub>C</sub>	$I_{PP}$ = 2.1 A, IEC61000–4–5 (1.2/50 μs), $R_{eq}$ = 12 $\Omega$		2.9	3.5	٧
Clamping Voltage 1.2/50 μs Waveform per Figure 12	V <sub>C</sub>	$I_{PP}$ = 3.5 A, IEC61000–4–5 (1.2/50 μs), $R_{eq}$ = 12 $\Omega$		3.6	4.0	V
Dynamic Resistance (TLP)	$R_{DYN}$	I/O Pin to GND (4 A to 8 A, 200 ns TLP)		0.34	0.5	Ω
Junction Capacitance	CJ	V <sub>R</sub> = 0 V, f = 1 MHz		0.17	0.20	pF
Insertion Loss	ΙL	f = 5 GHz f = 10 GHz		0.165 0.34	0.20 0.40	dB

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 2. For test procedure see application note AND8307/D.
- 3. ANSI/ESD STM5.5.1 Electrostatic Discharge Sensitivity Testing using Transmission Line Pulse (TLP) Model. TLP conditions:  $Z_0 = 50 \Omega$ ,  $t_p = 200$  ns,  $t_r = 4$  ns, averaging window;  $t_1 = 170$  ns to  $t_2 = 190$  ns.

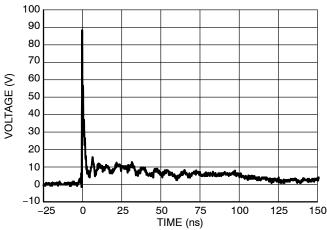


Figure 1. IEC61000-4-2 + 8 kV Contact ESD Clamping Voltage

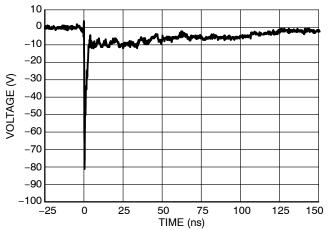


Figure 2. IEC61000-4-2 - 8 kV Contact ESD Clamping Voltage

# **ESDL2011**

# **TYPICAL CHARACTERISTICS**

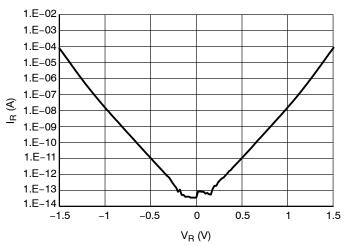


Figure 3. IV Characteristics

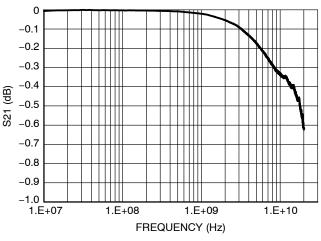


Figure 4. Insertion Loss

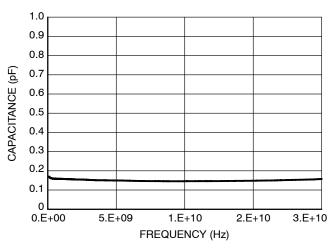


Figure 5. Typical Capacitance over Frequency

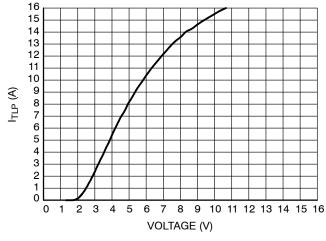


Figure 6. Positive 200 ns TLP IV Curve

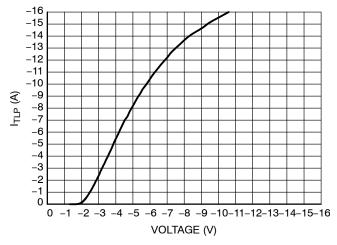


Figure 7. Negative 200 ns TLP IV Curve

# **ESDL2011**

# **TYPICAL CHARACTERISTICS**

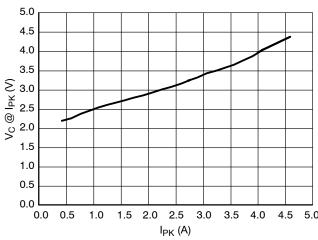


Figure 8. Positive Clamping Voltage vs. Peak Pulse Current (per IEC61000–4–5 (t $_p$  = 1.2/50  $\mu s,~R_{eq}$  = 12  $\Omega))$ 

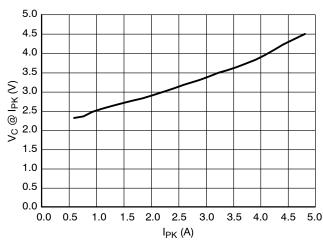


Figure 9. Negative Clamping Voltage vs. Peak Pulse Current (per IEC61000–4–5 (t $_p$  = 1.2/50  $\mu s,~R_{eq}$  = 12  $\Omega))$ 

# IEC 61000-4-2 Spec.

Level	Test Volt- age (kV)	First Peak Current (A)	Current at 30 ns (A)	Current at 60 ns (A)
1	2	7.5	4	2
2	4	15	8	4
3	6	22.5	12	6
4	8	30	16	8

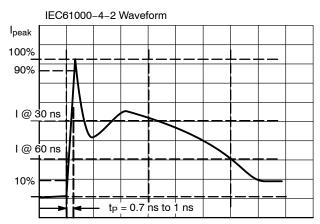


Figure 10. IEC61000-4-2 Spec

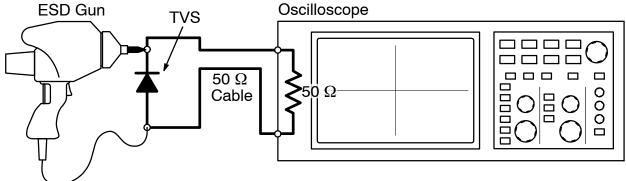


Figure 11. Diagram of ESD Test Setup

# **ESD Voltage Clamping**

For sensitive circuit elements it is important to limit the voltage that an IC will be exposed to during an ESD event to as low a voltage as possible. The ESD clamping voltage is the voltage drop across the ESD protection diode during an ESD event per the IEC61000-4-2 waveform. Since the IEC61000-4-2 was written as a pass/fail spec for larger systems such as cell phones or laptop computers it is not clearly defined in the spec how to specify a clamping voltage

at the device level. ON Semiconductor has developed a way to examine the entire voltage waveform across the ESD protection diode over the time domain of an ESD pulse in the form of an oscilloscope screenshot, which can be found on the datasheets for all ESD protection diodes. For more information on how ON Semiconductor creates these screenshots and how to interpret them please refer to AND8307/D.

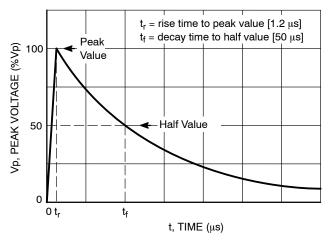


Figure 12. IEC61000-4-5 1.2/50 μs Pulse Waveform

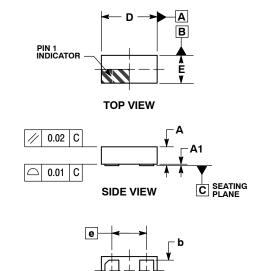


⊕ 0.05 M C

В

# X4DFN2, 0.60x0.30, 0.36P CASE 152AX **ISSUE G**

**DATE 12 APR 2019** 



**BOTTOM VIEW** 

⊕ | 0.05 M | C | A | B

- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.

	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	0.175	0.200	0.225	
A1	0.018 REF			
b	0.205	0.215	0.225	
D	0.575	0.600	0.625	
Е	0.275	0.300	0.325	
е	0.36 BSC			
L	0.145	0.155	0.165	

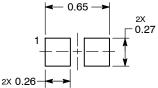
# **GENERIC MARKING DIAGRAM\***



# X = Specific Device Code

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G", may or not be present. Some products may not follow the Generic Marking.

## **RECOMMENDED SOLDER FOOTPRINT\***



DIMENSIONS: MILLIMETERS

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DOCUMENT NUMBER:	98AON06808G	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	X4DFN2, 0.60x0.30, 0.36P		PAGE 1 OF 1	

ON Semiconductor and (III) are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

ON Semiconductor and the are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor and see no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and

#### **PUBLICATION ORDERING INFORMATION**

LITERATURE FULFILLMENT:
Email Requests to: orderlit@onsemi.com

ON Semiconductor Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative

# **Mouser Electronics**

**Authorized Distributor** 

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

ON Semiconductor: ESDL2011PFCT5G